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JEOL Application Data Sheet

SEM (Atmospheric SEM *ClairScope*)

Slurry observation using ASEM

ClairScope is an instrument to observe specimens with the Atmospheric Scanning Electron Microscope (ASEM) and an Optical Microscope (OM). Since the specimen is always kept at normal atmospheric pressure and in liquid during observation, the native state of the specimens can be observed.





(a) ASEM observation.



(b) Easy mounting of a specimen on the ASEM dish without pretreatment.

Figure 1. ASEM observation method.



Figure 2. Silver paste. Distribution of particles with the size of tens of nm - 1 µm in real paste.







x15,000 scale bar: 1 µm

Figure 4. A swelling and delamination process of a layered compound after the addition of a reagent. (Courtesy of Dr. Y. Watanabe, Kanazawa Institute of Technology)

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